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# United States Patent [19]

Suzuki et al.

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[54] PROBE FOR MEASURING AN ELECTRIC CONDUCTIVITY

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[\*\*] Term: 14 Years

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[51] LOC (6) CL ..... 10-04

[52] U.S. Cl. .... D10/78; D10/80

[58] Field of Search ..... D10/80, 78; 324/72.5, 324/133, 149, 158, 501, 519, 527, 530, 555, 556

### [56] References Cited

#### U.S. PATENT DOCUMENTS

D. 367,236	2/1996	Groothuizen et al. ....	D10/81
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### [57] CLAIM

The ornamental design for a probe for measuring an electric conductivity, as shown and described.

### DESCRIPTION

FIG. 1 is a front, top and right side perspective view of a probe for measuring an electric conductivity, showing our new design;

FIG. 2 is a front elevational view thereof, the opposite side being a mirror image thereof;

FIG. 3 is a right side elevational view thereof;

FIG. 4 is a left side elevational view thereof;

FIG. 5 is a top plan view thereof;

FIG. 6 is a bottom plan view thereof; and,

FIG. 7 is a reference view showing the state of the probe drawn by a cable in the water of the sea in a suspended state; and the broken lines depicting environmental circumstances of the present article form no part of the claimed design.

1 Claim, 2 Drawing Sheets



FIG. 1

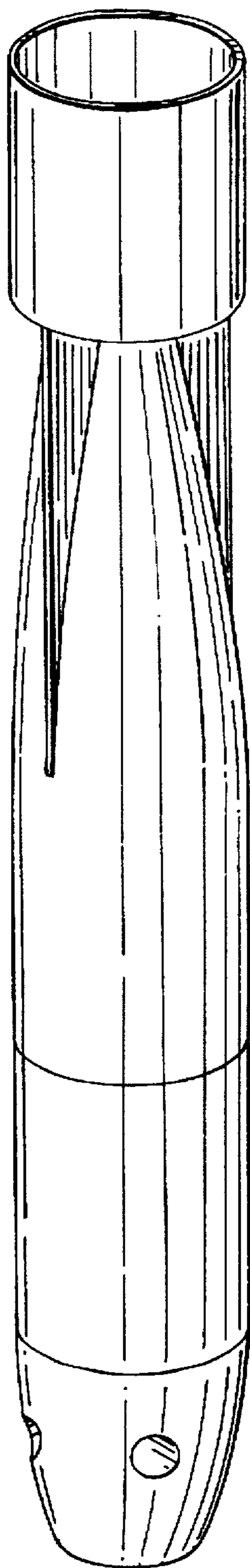


FIG. 2

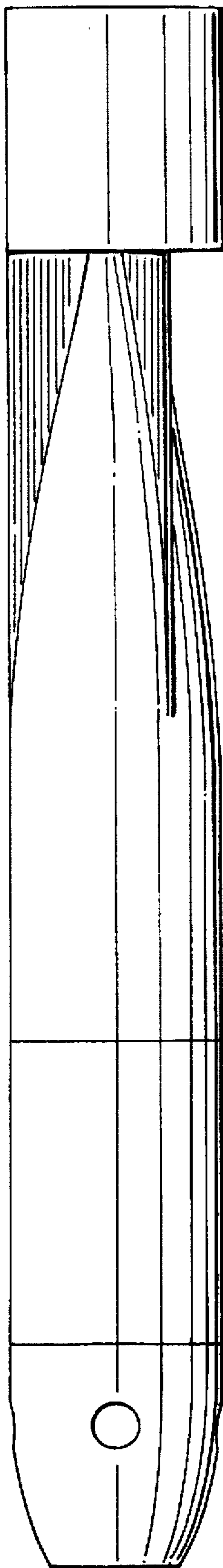


FIG. 3

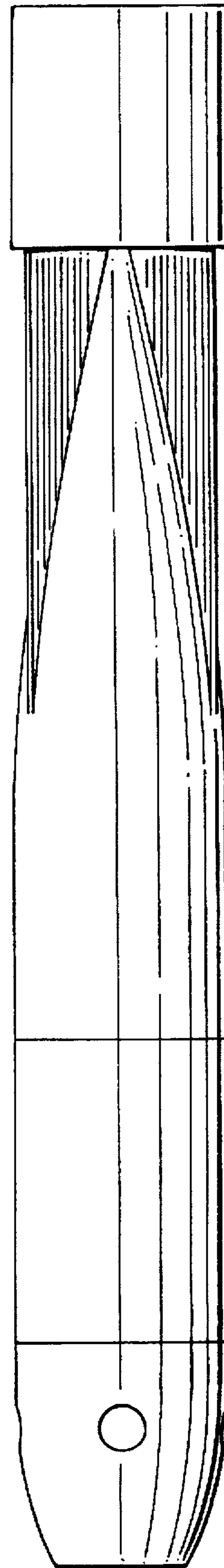


FIG. 4

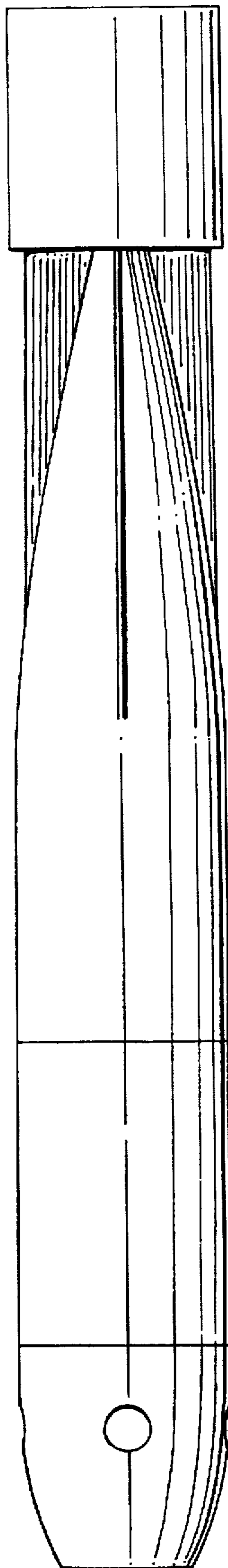


FIG. 5

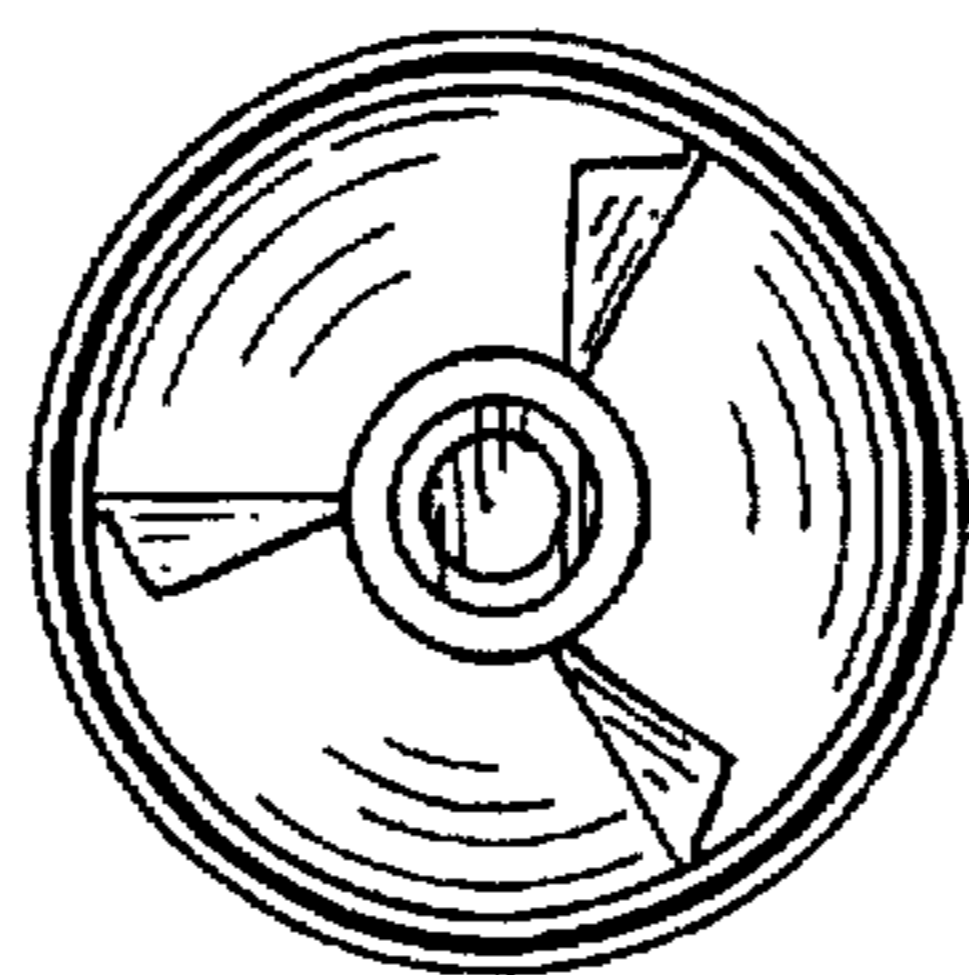


FIG. 6

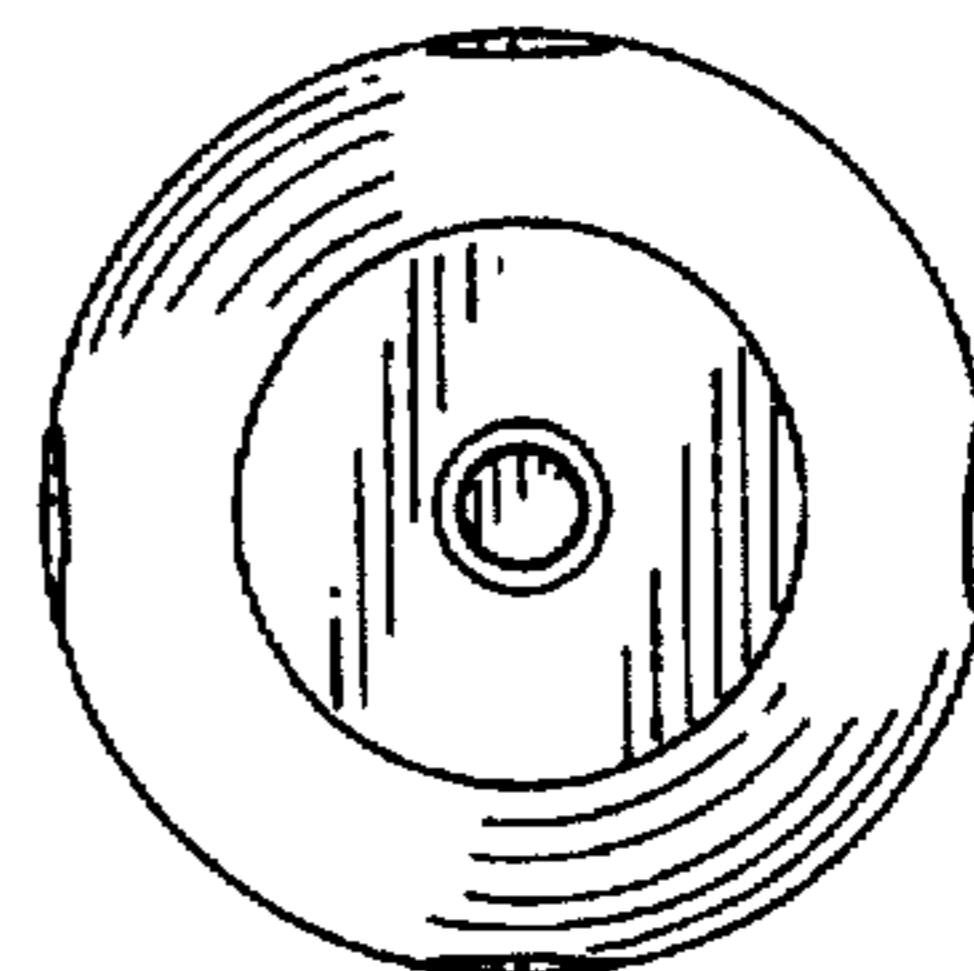


FIG. 7

